

Notice of References Cited	Application/Control No. 10/729,944	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,118,502	09-2000	Yamazaki et al.	349/45
	B	US-6,309,902	10-2001	Muramatsu, Eiji	438/30
	C	US-6,829,030	12-2004	Hagiwara, Takeshi	349/149
	D	US-6,769,782	08-2004	Lee, Jeong-Hwan	362/600
	E	US-6,518,944	02-2003	Doane et al.	345/87
	F	US-6,496,767	12-2002	Lorentz, Timothy Alan	701/55
	G	US-2002/0017682	02-2002	Xu et al.	257/328
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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